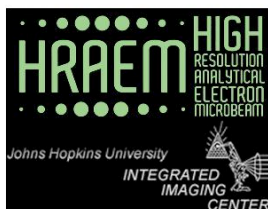


Agenda of the 2011 FIB SEM Meeting Feb. 25, 2011

Mason Hall, Johns Hopkins University

Time	Speaker	Affiliation	Title
8:30	Breakfast		
9:00	Ken Livi	JHU	Welcome
9:10	Brenton Knuffman	NIST	Development of Li Focused Ion Beam
9:40	Brian Schuster	ARL	FIB applications for the Army
10:00	Lynne Gignac	IBM	Multiple double XTEM Sample Preparation of Sub-10nm Diameter Si nanowires
10:20	Valery Ray	PBS&T	Advanced FIB Circuit Edit: Cu Line Deprocessing
10:40	Break		
11:00	Richard Wirth	Potsdam	Advanced Applications in FIB-TEM in Geosciences
11:30	Gavin Murphy & Kedar Narayan	NIH	Correlated 3D Imaging of cells with Light Microscopy and Ion Abrasion-Scanning Electron Microscopy
11:50	Todd Brintlinger	NRL	TBD
12:10	Lunch		
1:00	Poster Session		
2:00	Noel Smith	Oregon Phy.	Plasma-FIB for High Throughput Micromachining and Large Volume Sample Preparation
2:20	Jason Haung	Carl Zeiss	New Applications of XeF2 Chemistry with Ga FIB
2:40	Mike Marsh	VSG	Solutions and Case Studies of 3D Interpretation for FIB-TEM Tomography
3:00	Andrew Smith	Kleindiek	Precision Tools for Enhancing your FIB- Give Your Microscope a Hand
3:20	Break		
3:40	Roger Alvis	FEI	TBD
4:20	Arno Merkle	Carl Zeiss	Precise Nano-machining with Highly-Focused Inert Gas Ion Beams
4:40	Cheryl Hartfield	Omniprobe	Optimizing <i>In Situ</i> Lift-Out
5:00	Ken Livi	JHU	Wrap Up
5:30	Happy Hour		
8:00	Departures		

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